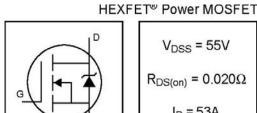
International IOR Rectifier

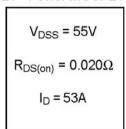
- Advanced Process Technology
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated
- Lead-Free

Description

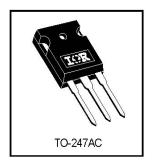
Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The TO-247 package is preferred for commercial-industrial applications where higher power levels preclude the use of TO-220 devices. The TO-247 is similar but superior to the earlier TO-218 package because of its isolated mounting





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Absolute Maximum Ratings

	Parameter	Max.	Units	
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V	53		
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V	37	Α	
I _{DM}	Pulsed Drain Current ①⑤	180		
P _D @T _C = 25°C	Power Dissipation	120	W	
	Linear Derating Factor	0.77	W/°C	
V _{GS}	Gate-to-Source Voltage	± 20	V	
E _{AS}	Single Pulse Avalanche Energy@⑤	230	mJ	
l _{AR}	Avalanche Current®	28	Α	
E _{AR}	Repetitive Avalanche Energy®	12	mJ	
d∨/dt	Peak Diode Recovery dv/dt ③⑤	5.0	V/ns	
TJ	Operating Junction and	-55 to + 175		
T _{STG}	Storage Temperature Range		°C	
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)		
	Mounting torque, 6-32 or M3 screw	10 lbf•in (1.1N•m)		

Thermal Resistance

	Parameter	Тур.	Max.	Units
R _{⊎JC}	Junction-to-Case		1.3	
R _{ecs}	Case-to-Sink, Flat, Greased Surface	0.24		°C/W
Reja	Junction-to-Ambient		40	

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Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

Parameter	Min.	Тур.	Max.	Units	Conditions
Drain-to-Source Breakdown Voltage	55			V	$V_{GS} = 0V$, $I_{D} = 250 \mu A$
Breakdown Voltage Temp. Coefficient		0.017		V/°C	Reference to 25°C, ID = 1mAS
Static Drain-to-Source On-Resistance			0.020	Ω	V _{GS} = 10V, I _D = 29A ④
Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}$, $I_D = 250\mu A$
Forward Transconductance	16			S	$V_{DS} = 25V, I_{D} = 28A$ §
Drain-to-Source Leakage Current			25		$V_{DS} = 55V$, $V_{GS} = 0V$
			250	μA	$V_{DS} = 44V, V_{GS} = 0V, T_{J} = 150^{\circ}C$
Gate-to-Source Forward Leakage			100	n A	V _{GS} = 20V
Gate-to-Source Reverse Leakage			-100	IIA I	V _{GS} = -20V
Total Gate Charge			61		I _D = 28A
Gate-to-Source Charge	2 2 2	1-10	13	nC	V _{DS} = 44V
Gate-to-Drain ("Miller") Charge			24		V _{GS} = 10V, See Fig. 6 and 13 ⊕ ⑤
Turn-On Delay Time	14 15 15	12			V _{DD} = 28V
Rise Time		80			I _D = 28A
Turn-Off Delay Time	14 15 #	43		ns	$R_G = 12\Omega$
Fall Time	-	52	-		R _D = 0.98Ω, See Fig. 10 ④⑤
Internal Drain Inductance		5.0	_	in sid	Between lead, 6mm (0.25in.)
Internal Source Inductance	_	13	_	nH	from package and center of die contact
Input Capacitance		1500			V _{GS} = 0V
Output Capacitance		450		pF	V _{DS} = 25V
Reverse Transfer Capacitance		160			f = 1.0MHz, See Fig. 5⑤
	Drain-to-Source Breakdown Voltage Breakdown Voltage Temp. Coefficient Static Drain-to-Source On-Resistance Gate Threshold Voltage Forward Transconductance Drain-to-Source Leakage Current Gate-to-Source Forward Leakage Gate-to-Source Reverse Leakage Total Gate Charge Gate-to-Drain ("Miller") Charge Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Internal Drain Inductance Internal Source Inductance Input Capacitance Output Capacitance	Drain-to-Source Breakdown Voltage Breakdown Voltage Temp. Coefficient Static Drain-to-Source On-Resistance Gate Threshold Voltage Forward Transconductance Drain-to-Source Leakage Current Gate-to-Source Forward Leakage Gate-to-Source Reverse Leakage Total Gate Charge Gate-to-Source Charge Gate-to-Drain ("Miller") Charge Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Internal Drain Inductance Internal Source Inductance Input Capacitance Output Capacitance ———————————————————————————————————	Drain-to-Source Breakdown Voltage 55 — Breakdown Voltage Temp. Coefficient — 0.017 Static Drain-to-Source On-Resistance — — Gate Threshold Voltage 2.0 — Forward Transconductance 16 — Drain-to-Source Leakage Current — — Gate-to-Source Forward Leakage — — Gate-to-Source Reverse Leakage — — Gate-to-Source Charge — — Gate-to-Source Charge — — Gate-to-Drain ("Miller") Charge — — Turn-On Delay Time — 12 Rise Time — 80 Turn-Off Delay Time — 43 Fall Time — 52 Internal Drain Inductance — 5.0 Internal Source Inductance — 13 Input Capacitance — 450	Drain-to-Source Breakdown Voltage 55 — — Breakdown Voltage Temp. Coefficient — 0.017 — Static Drain-to-Source On-Resistance — — 0.020 Gate Threshold Voltage 2.0 — 4.0 Forward Transconductance 16 — — Drain-to-Source Leakage Current — — 25 — — 250 — — 25 Gate-to-Source Forward Leakage — — 100 — 61 — — 61 — — 61 — — 61 — — 61 — — 61 — — 61 — — 61 — — 61 — — 24 — — 61 — — 24 — — 61 — — 24 — — 24 — — 24 — — 24 — — —	Drain-to-Source Breakdown Voltage 55 — V Breakdown Voltage Temp. Coefficient — 0.017 — V/°C Static Drain-to-Source On-Resistance — — 0.020 Ω Gate Threshold Voltage 2.0 — 4.0 V Forward Transconductance 16 — — S Drain-to-Source Leakage Current — — 25 μA Gate-to-Source Forward Leakage — — 100 nA Gate-to-Source Reverse Leakage — — 100 nA Gate-to-Source Charge — — 61 nC Gate-to-Source Charge — — 13 nC Gate-to-Source Charge — — 13 nC Gate-to-Drain ("Miller") Charge — — 24 Turn-On Delay Time — 12 — Rise Time — 80 — Fall Time — 52 — Internal Drain I

Source-Drain Ratings and Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current					MOSFET symbol
	(Body Diode))		53	A	showing the
I _{SM}	Pulsed Source Current			400		integral reverse
	(Body Diode) ①			180		p-n junction diode.
V _{SD}	Diode Forward Voltage			1.3	V	T _J = 25°C, I _S = 29A, V _{GS} = 0V ④
t _{rr}	Reverse Recovery Time		72	110	ns	T _J = 25°C, I _F = 28A
Qm	Reverse Recovery Charge	7500 10	210	310	μC	di/dt = -100A/µs ⊕ ⑤
ton	Forward Turn-On Time	Intr	Intrinsic turn-on time is negligible (turn-on is dominated by L_S+L_D)			

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- $\label{eq:loss_def} \begin{tabular}{ll} \begin{tabular}{ll} $I_{SD} \le 28A, \ di/dt \le 240A/\mu s, \ V_{DD} \le V_{(BR)DSS}, \\ $T_{J} \le 175^{\circ}C$ \end{tabular}$
- 4 Pulse width $\leq 300 \mu s$; duty cycle $\leq 2\%$.
- © Uses IRFZ46N data and test conditions

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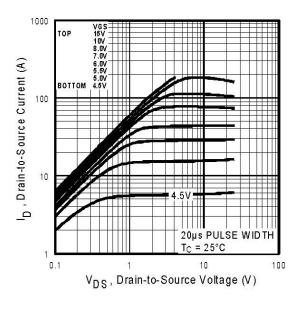


Fig 1. Typical Output Characteristics

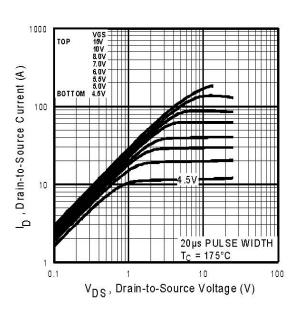


Fig 2. Typical Output Characteristics

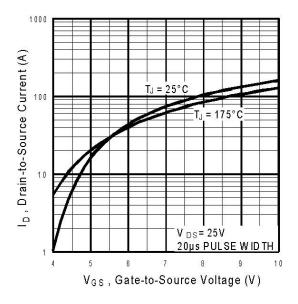


Fig 3. Typical Transfer Characteristics

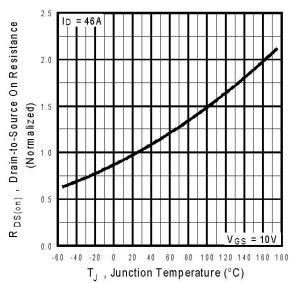
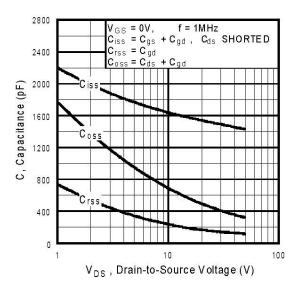


Fig 4. Normalized On-Resistance Vs. Temperature

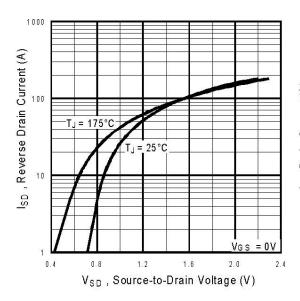


O 10 20 30 40 50 60

Q G, Total Gate Charge (nC)

Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage



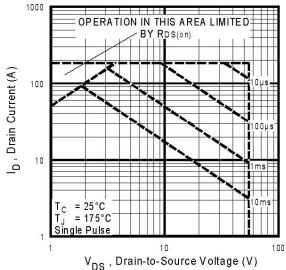
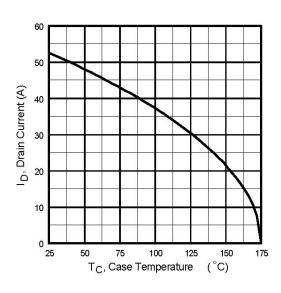


Fig 7. Typical Source-Drain Diode Forward Voltage

Fig 8. Maximum Safe Operating Area

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 V_{DS} V_{DS} V

Fig 10a. Switching Time Test Circuit

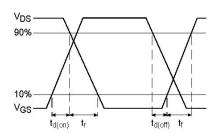


Fig 9. Maximum Drain Current Vs. Case Temperature

Fig 10b. Switching Time Waveforms

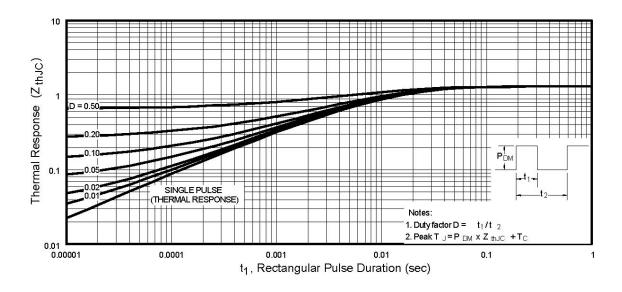


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

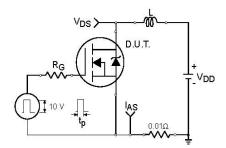


Fig 12a. Unclamped Inductive Test Circuit

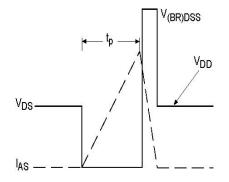


Fig 12b. Unclamped Inductive Waveforms

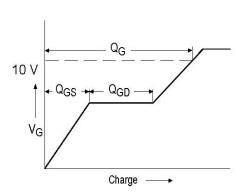


Fig 13a. Basic Gate Charge Waveform

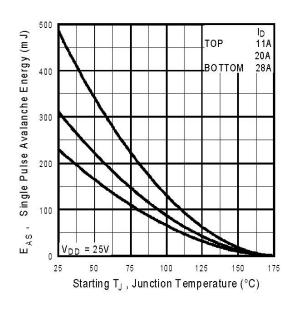


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

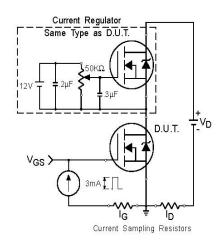
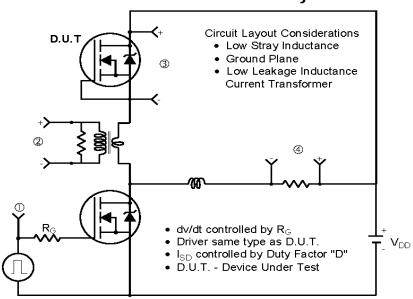


Fig 13b. Gate Charge Test Circuit

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Peak Diode Recovery dv/dt Test Circuit



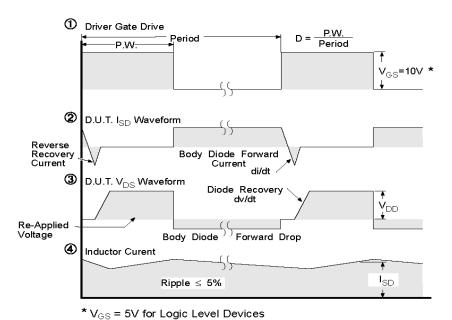


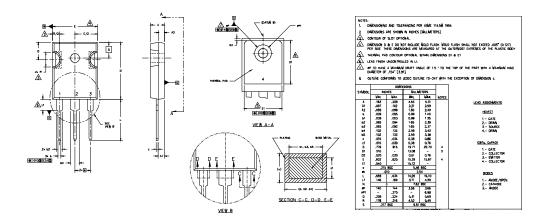
Fig 14. For N-Channel HEXFETS

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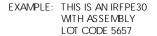
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TO-247AC Package Outline

Dimensions are shown in millimeters (inches)

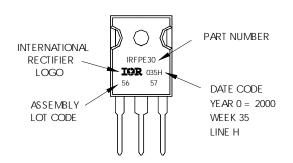


TO-247AC Part Marking Information



ASSEMBLED ON WW 35, 2000 IN THE ASSEMBLY LINE "H"

Note: "P" in assembly line position indicates "Lead-Free"



Data and specifications subject to change without notice.



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Note: For the most current drawings please refer to the IR website at: http://www.irf.com/package/

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